


<b>Search Notes</b> 	<b>Application/Control No.</b> 10573198	<b>Applicant(s)/Patent Under Reexamination</b> TANAKA ET AL.
	<b>Examiner</b> Phan, Thiem D	<b>Art Unit</b> 3729

SEARCHED			
Class	Subclass	Date	Examiner
29	598, 596, 605, 606, 734, 736	4/20/09	TP
310	214-216	"	"
524	714, 718, 719	"	"

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search Attached	4/20/09	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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